

R1RP0408D Series

R10DS0288EJ0100 Rev.1.00 Nov.18.19

4M High Speed SRAM (512-kword × 8-bit)

Description

The R1RP0408D Series is a 4-Mbit high speed static RAM organized 512-k word \times 8-bit. It has realized high speed access time by employing CMOS process (6-transistor memory cell) and high speed circuit designing technology. It is most appropriate for the application which requires high speed, high density memory and wide bit width configuration, such as cache and buffer memory in system. It is packaged in 400-mil 36-pin plastic SOJ.

Features

• Single 5.0V supply: 5.0V ± 10%

Access time: 12ns (max)

· Completely static memory

No clock or timing strobe required

• Equal access and cycle times

• Directly TTL compatible

All inputs and outputs

• Operating current: 130mA (max)

• TTL standby current: 40mA (max)

• CMOS standby current : 5mA (max)

: 1.0mA (max) (L-version)

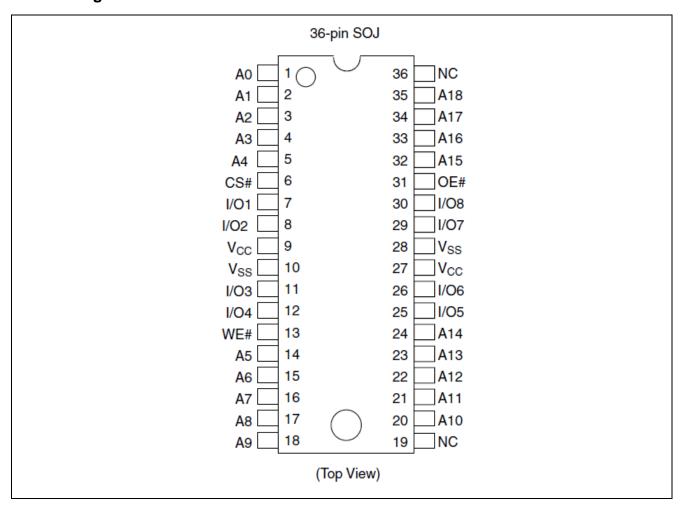
Data retention current : 0.5mA (max) (L-version)
Data retention voltage : 2.0V (min) (L-version)

Center Vcc and Vss type pin out

Ordering Information

Type No.	Access time	Version	Package
R1RP0408DGE-2PR	12ns	Normal	400 mil 20 min mlantin CO l
R1RP0408DGE-2LR	12ns	L-Version	400-mil 36-pin plastic SOJ

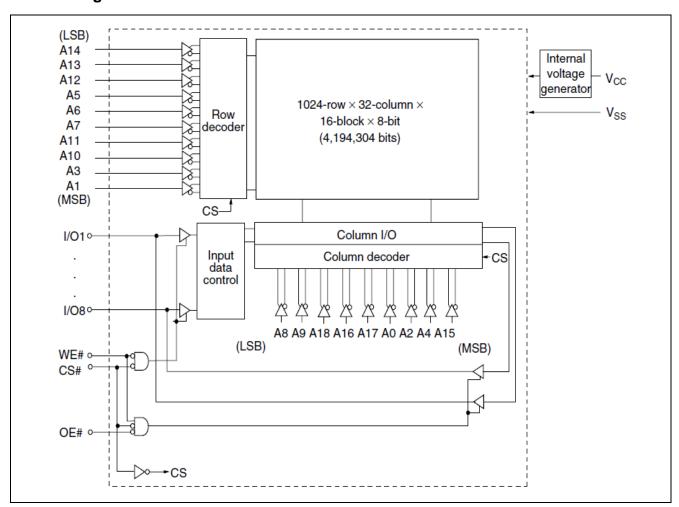
Pin Arrangement



Pin Description

Pin name	Function
A0 to A18	Address input
I/O1 to I/O8	Data input/output
CS#	Chip select
OE#	Output enable
WE#	Write enable
Vcc	Power supply
Vss	Ground
NC	No connection

Block Diagram



Operation Table

CS#	OE#	WE#	Mode	Vcc current	I/O	Ref. cycle
Н	×	×	Standby	I _{SB} , I _{SB1}	High-Z	_
L	Н	Н	Output disable	Icc	High-Z	_
L	L	Н	Read	Icc	D _{OUT}	Read cycle (1) to (3)
L	Н	L	Write	Icc	D _{IN}	Write cycle (1)
L	L	L	Write	Icc	D _{IN}	Write cycle (2)

Note: H: VIH, L: VIL, X: VIH or VIL

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Supply voltage relative to V _{SS}	V _{CC}	−0.5 to +7.0	V
Voltage on any pin relative to Vss	VT	-0.5*1 to V _{CC} + 0.5*2	V
Power dissipation	PT	1.0	W
Operating temperature	Topr	0 to +70	°C
Storage temperature	Tstg	−55 to +125	°C
Storage temperature under bias	Tbias	−10 to +85	°C

Notes: 1. V_T (min) = -2.0V for pulse width (under shoot) \leq 6ns.

2. V_T (max) = V_{CC} + 2.0V for pulse width (over shoot) \leq 6ns.

Recommended DC Operating Conditions

 $(Ta = 0 \text{ to } +70^{\circ}C)$

Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage	Vcc*3	4.5	5.0	5.5	V
	Vss*4	0	0	0	V
Input voltage	ViH	2.0	_	Vcc + 0.5*2	V
	VIL	-0.5* ¹	_	0.8	V

Notes: 1. V_{IL} (min) = -2.0V for pulse width (under shoot) \leq 6ns.

- 2. V_{IH} (max) = V_{CC} + 2.0V for pulse width (over shoot) \leq 6ns.
- 3. The supply voltage with all V_{CC} pins must be on the same level.
- 4. The supply voltage with all V_{SS} pins must be on the same level.

DC Characteristics

 $(Ta = 0 \text{ to } +70^{\circ}\text{C}, V_{CC} = 5.0\text{V} \pm 10\%, V_{SS} = 0\text{V})$

Parameter	Symbol	Min	Max	Unit	Test conditions
Input leakage current	I _{LI}	_	2	μΑ	$V_{IN} = V_{SS}$ to V_{CC}
Output leakage current	I _{LO}	_	2	μΑ	$V_{IN} = V_{SS}$ to V_{CC}
Operating power supply current	Icc	_	130	mA	Min cycle $CS\# = V_{IL}, I_{OUT} = 0mA$ Other inputs = V_{IH}/V_{IL}
Standby power supply current	I _{SB}	_	40	mA	Min cycle, CS# = V _{IH} , Other inputs = V _{IH} /V _{IL}
	I _{SB1}	_	5	mA	
		<u></u> *1	1.0* ¹	mA	(1) $0V \le V_{IN} \le 0.2V$ or (2) $V_{CC} \ge VIN \ge V_{CC} - 0.2V$
Output voltage	Vol	_	0.4	V	$I_{OL} = 8mA$
	Vон	2.4	_	V	I _{OH} = -4mA

Note: 1. This characteristics is guaranteed only for L-version.

Capacitance

 $(Ta = +25^{\circ}C, f = 1.0MHz)$

Parameter	Symbol	Min	Max	Unit	Test conditions
Input capacitance*1	Cin	_	6	pF	V _{IN} = 0V
Input/output capacitance*1	C _{I/O}		8	pF	V _{I/O} = 0V

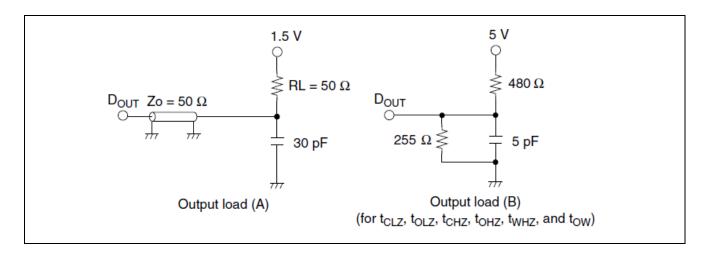
Note: 1. This parameter is sampled and not 100% tested.

AC Characteristics

Test Conditions (Ta = 0 to +70°C, VCC = $5.0V \pm 10\%$, unless otherwise noted.)

Input pulse levels: 3.0V/0.0VInput rise and fall time: 3ns

Input and output timing reference levels: 1.5VOutput load: See figures (Including scope and jig)



Read Cycle

		R1RP0408D			
Parameter	Symbol	Min	Max	Unit	Notes
Read cycle time	t _{RC}	12	_	ns	
Address access time	taa	_	12	ns	
Chip select access time	tacs	_	12	ns	
Output enable to output valid	toe	_	6	ns	
Output hold from address change	tон	3	_	ns	
Chip select to output in low-Z	tcLZ	3	_	ns	1
Output enable to output in low-Z	tolz	0	_	ns	1
Chip deselect to output in high-Z	tснz	_	6	ns	1
Output disable to output in high-Z	tонz	_	6	ns	1

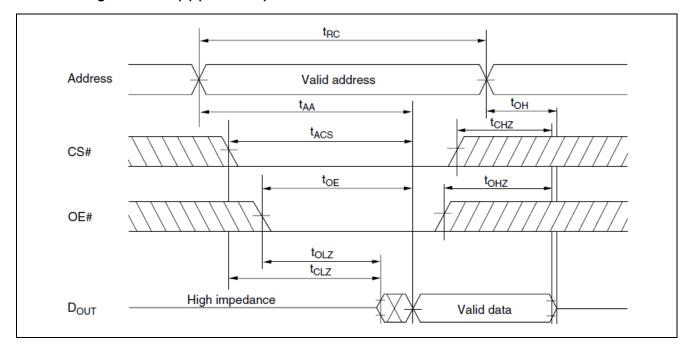
Write Cycle

		R1RP	0408D		
Parameter	Symbol	Min	Max	Unit	Notes
Write cycle time	twc	12	_	ns	
Address valid to end of write	t _{AW}	8	_	ns	
Chip select to end of write	tcw	8	_	ns	9
Write pulse width	twp	8	_	ns	8
Address setup time	t _{AS}	0	_	ns	6
Write recovery time	twR	0	_	ns	7
Data to write time overlap	t _{DW}	6	_	ns	
Data hold from write time	tон	0	_	ns	
Write disable to output in low-Z	tow	3	_	ns	1
Output disable to output in high-Z	tонz	_	6	ns	1
Write enable to output in high-Z	t _{WHZ}	_	6	ns	1

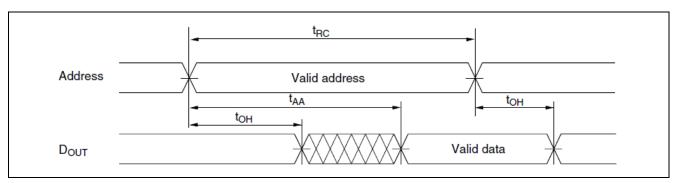
- Notes: 1. Transition is measured ± 200 mV from steady voltage with output load (B). This parameter is sampled and not 100% tested.
 - 2. Address should be valid prior to or coincident with CS# transition low.
 - 3. WE# and/or CS# must be high during address transition time.
 - 4. If CS# and OE# are low during this period, I/O pins are in the output state. Then, the data input signals of opposite phase to the outputs must not be applied to them.
 - 5. If the CS# low transition occurs simultaneously with the WE# low transition or after the WE# transition, output remains a high impedance state.
 - 6. t_{AS} is measured from the latest address transition to the later of CS# or WE# going low.
 - 7. twR is measured from the earlier of CS# or WE# going high to the first address transition.
 - 8. A write occurs during the overlap of a low CS# and a low WE#. A write begins at the latest transition among CS# going low and WE# going low. A write ends at the earliest transition among CS# going high and WE# going high. twp is measured from the beginning of write to the end of write.
 - 9. t_{CW} is measured from the later of CS# going low to the end of write.

Timing Waveforms

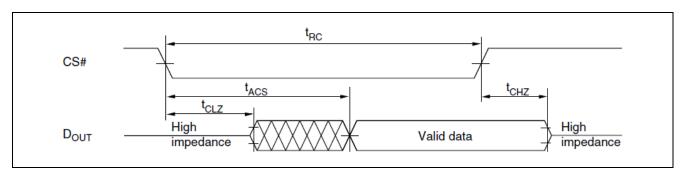
Read Timing Waveform (1) (WE# = V_{IH})



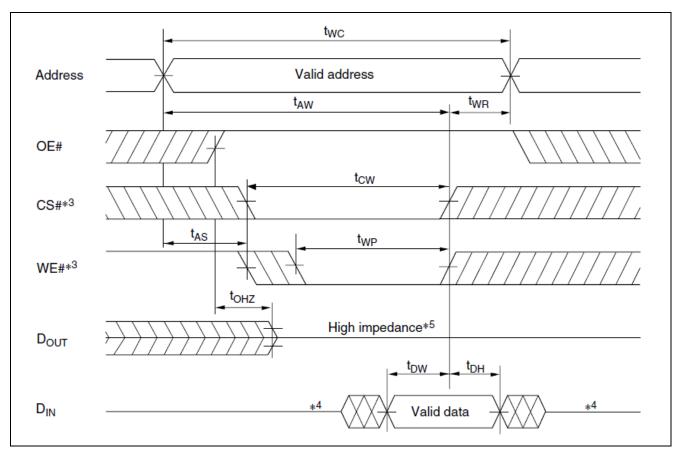
Read Timing Waveform (2) (WE# = V_{IH} , LB# = V_{IL} , UB# = V_{IL})



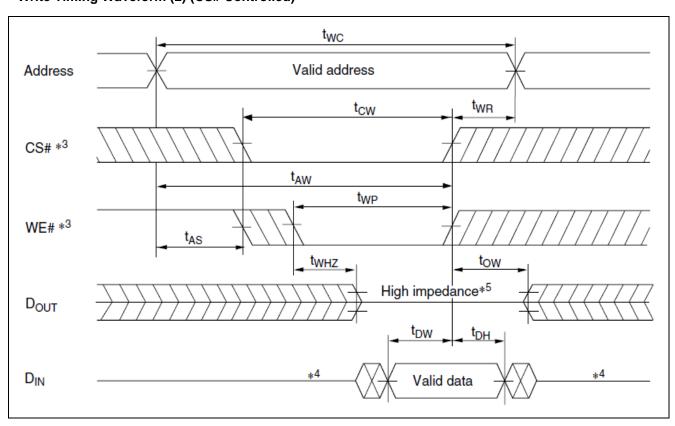
Read Timing Waveform (3) (WE# = V_{IH} , CS# = V_{IL} , OE# = V_{IL})*2



Write Timing Waveform (1) (WE# Controlled)



Write Timing Waveform (2) (CS# Controlled)



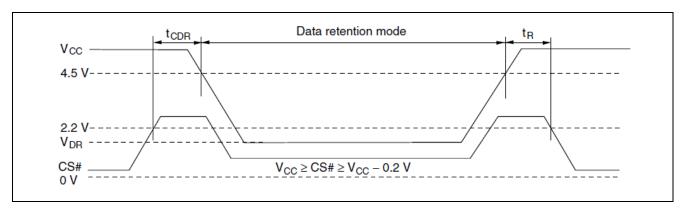
Low Vcc Data Retention Characteristics

 $(Ta = 0 \text{ to } +70^{\circ}C)$

This characteristics is guaranteed only for L-version.

Parameter	Symbol	Min	Max	Unit	Test conditions
Vcc for data retention	V _{DR}	2.0	_	V	$V_{CC} \ge CS\# \ge V_{CC} - 0.2V,$ (1) $0 \ V \le V_{IN} \le 0.2V \ or$ (2) $V_{CC} \ge V_{IN} \ge V_{CC} - 0.2V$
Data retention current	ICCDR	_	500	μΑ	$V_{CC} = 3V$ $V_{CC} \ge CS\# \ge V_{CC} - 0.2V$, (1) $0V \le V_{IN} \le 0.2V$ or (2) $V_{CC} \ge V_{IN} \ge V_{CC} - 0.2V$
Chip deselect to data retention time	t _{CDR}	0	_	ns	See retention waveform
Operation recovery time	t _R	5	_	ms	

Low V_{CC} Data Retention Timing Waveform



Revision History

		Description				
Rev.	Date	Page	Summary			
1.00	Nov.18.19	-	First Edition issued			

All documents should contain the following section break and paragraph as the last item. The footers of this document refer to the paragraph in order to reference the last page of the document.

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(Rev.1.0 Mar 2020)

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